

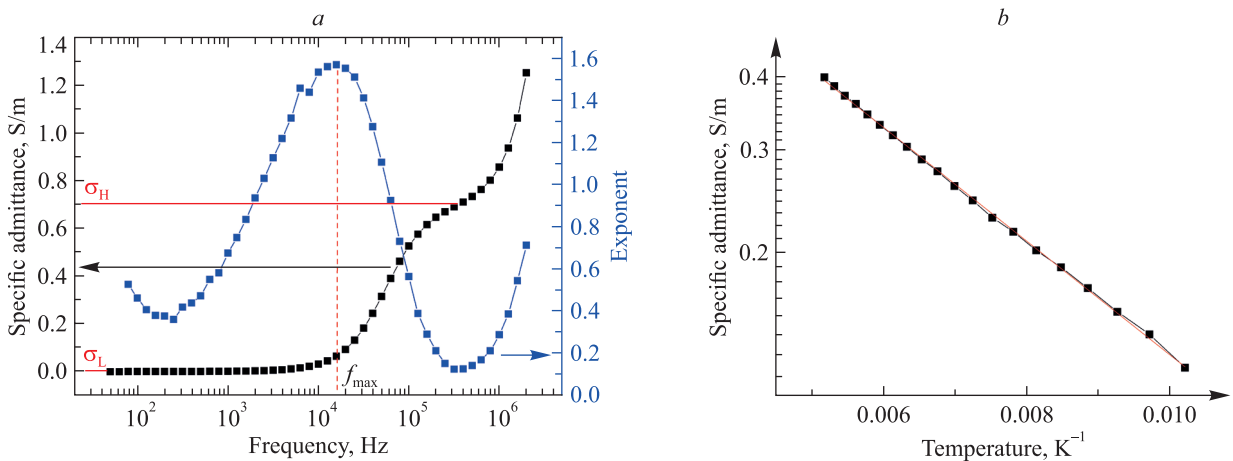


Fig. 1. Examples of the frequency dependence of the real part of the specific admittance $\sigma(f)$ and the exponent $\alpha(f)$ in relation (1) for the $(\text{Fe}_{0.45}\text{Co}_{0.45}\text{Zr}_{0.10})_{0.52}(\text{PZT})_{0.48}$ film deposited in Ar – O₂ mixture under $P_{\text{O}_2} = 2.0 \cdot 10^{-3}$ Pa and $T = 223$ K (a) and Arrhenius curves for $f = 500$ Hz in the region of low T for the film $(\text{Fe}_{0.45}\text{Co}_{0.45}\text{Zr}_{0.10})_{0.31}(\text{Al}_2\text{O}_3)_{0.69}$ deposited in an Ar and annealed at $T_{\text{an}} = 623$ K (b)